

DOCKET NO: 287800US26PCT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

:

MASAYUKI OIKAWA, ET AL.

: EXAMINER: CHAN, CEDRIC A.

SERIAL NO: 10/574,286

:

FILED: MARCH 31, 2006

: GROUP ART UNIT: 1773

FOR: INSPECTION METHOD AND
INSPECTION ASSISTING DEVICE FOR
QUARTZ PRODUCT OF
SEMICONDUCTOR PROCESSING
APPARATUS

:

AMENDMENT UNDER 37 C.F.R. § 1.116

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated March 31, 2011, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 8 of this paper.